

FIGURE 15.6 1-kHz sine wave sampled at the Nyquist frequency.

When a data conversion circuit is operated above the Nyquist frequency, *aliasing* develops, which distorts the information content of a signal. Aliasing occurs when a high-frequency signal is made to appear as a low-frequency signal as a result of inadequate sampling. Assume that a 1-kHz input is expected and a 3-kHz sampling rate is designed to satisfy the Nyquist theorem with some margin. For some reason, a 2-kHz signal enters the system. Figure 15.7 shows how this signal might be sampled. The 333 μ s sampling interval is too slow to capture each 250 μ s high and low phase of the 2-kHz signal. As a result, the samples convey information that is drastically different from the input. Instead of 2 kHz, the high-low-high interval of the samples indicates a 1-kHz signal! This 1-kHz aliased signal is the difference between the sampling rate and the actual signal frequency.

Aliasing applies to the analog-to-digital conversion process. When converting from digital to analog, the DAC is inherently self-limited by the sampling rate such that the highest frequency it can generate is half the sampling rate, or the Nyquist frequency. This behavior would result if consecu-

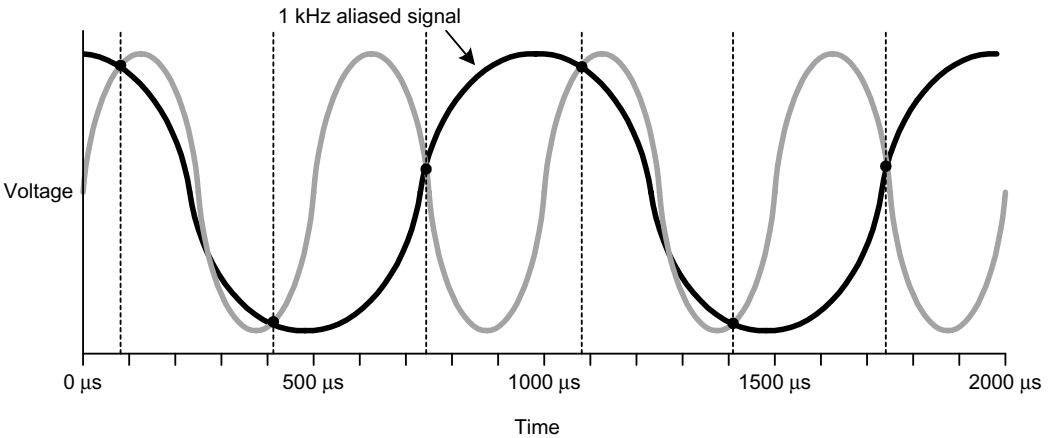


FIGURE 15.7 2-kHz sine wave sampled at 3 kHz with aliasing to 1 kHz.

tive samples alternated voltage levels about some DC level. A suitable lowpass filter on the DAC's output would remove the high-frequency edges and leave behind a sine wave of half the sampling frequency as shown in Fig. 15.8.

Lowpass filtering is a critical part of the data conversion process, because it removes unwanted sampling artifacts at DAC outputs and prevents aliasing at ADC inputs. The necessary slope of the filter's roll-off depends on how close unwanted high frequencies are to the Nyquist frequency.

15.3 ADC CIRCUITS

ADCs are available in a wide range of sampling rates and resolutions. The basic internal architecture of an ADC is straightforward, as shown in Fig. 15.9. A *sample and hold* (S/H) circuit captures a snapshot of the analog input signal so that the conversion circuit can work with a fixed sample over the conversion interval, which can be as long as the sampling interval. An ideal S/H circuit captures the input signal in zero time so that a true instantaneous sample is taken. In reality, the small capacitor that is used to hold the sample during conversion takes a finite time to charge through a finite switch resistance to the same voltage as the input. Once the conversion circuit maps the captured voltage to a digital sample, the digital interface conveys this information to the digital processor. ADC interfaces are available in both serial and parallel configurations.

A variety of basic analog-to-digital conversion circuits are used, based on the desired sampling rate and resolution. Three of the most common are *flash*, *successive-approximation*, and *sigma-delta*. A flash ADC, shown in Fig. 15.10, consists of a bank of parallel comparators, each fed by a unique incremental reference voltage. Each comparator's output represents one of the $2^N - 1$ possible outputs of the ADC. By process of elimination, the lowest quantum is not represented by a comparator, because it is implied if none of the comparators are at logic 1. Therefore, a 12-bit flash ADC

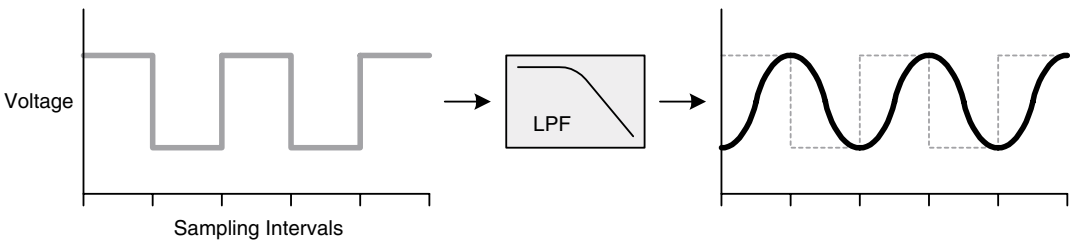


FIGURE 15.8 Maximum frequency output of the DAC.

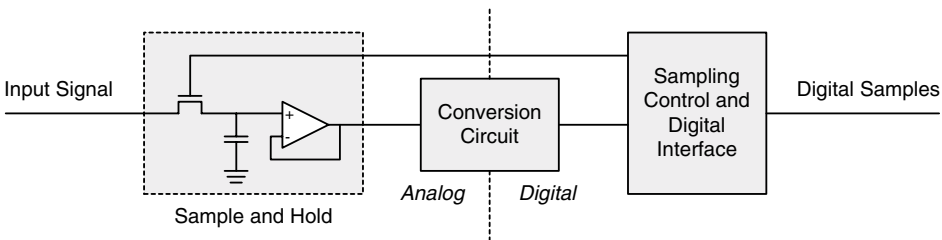


FIGURE 15.9 Basic ADC architecture.